

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant(s): Rankin, *et al.*

Examiner: Doty, Heather Anne

Serial No.: 10/710,602

Group Art Unit: 2813

Filed: 07/23/2004

Docket No.: **BUR920040086US1**

**Title: METHOD TO SELECTIVELY CORRECT CRITICAL DIMENSION ERRORS IN  
THE SEMICONDUCTOR INDUSTRY**

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Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**OFFICE ACTION RESPONSE**

Sir:

This communication is in response to the Final Office Action mailed August 21, 2006.